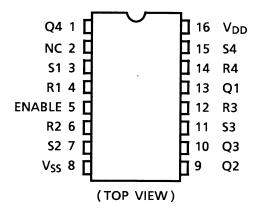
TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC4044BP,TC4044BF,TC4044BFN

TC4044B Quad 3-State R/S Latch (quad NAND R/S latch)

TC4044B the latches composed by four independent R/S flip-flop circuits. TC4044B fabricated with NAND gates is suitable for data processing of four bits configuration. Four output lines can have high impedance regardless of the contents of latches by means of common ENABLE input to make connection to the bus lines easy.

#### **Pin Assignment**



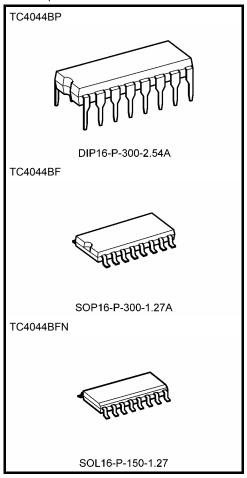
#### **Truth Table**

R	S	Е	Q
*	*	L	HZ
L	L	Н	L
L	Н	Н	L
Н	L	Н	Н
Н	Н	Н	No Change

\*: Don't care

HZ: High impedance

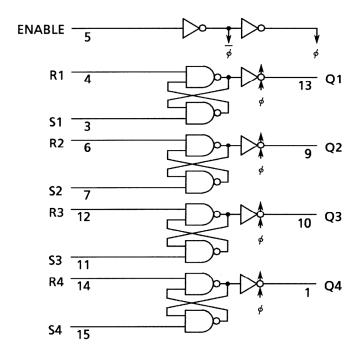
Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.) SOL16-P-150-1.27 : 0.13 g (typ.)

#### **Logic Diagram**



#### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	$V_{SS}$ – 0.5 to $V_{SS}$ + 20	V
Input voltage	V <sub>IN</sub>	$V_{SS}$ – 0.5 to $V_{DD}$ + 0.5	V
Output voltage	V <sub>OUT</sub>	V <sub>SS</sub> – 0.5 to V <sub>DD</sub> + 0.5	V
DC input current	I <sub>IN</sub>	±10	mA
Power dissipation	PD	300 (DIP)/180 (SOIC)	mW
Operating temperature range	T <sub>opr</sub>	-40 to 85	°C
Storage temperature range	T <sub>stg</sub>	-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### Operating Ranges ( $V_{SS} = 0 V$ ) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	$V_{DD}$	_	3	_	18	V
Input voltage	V <sub>IN</sub>	_	0	_	$V_{DD}$	V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .



## Static Electrical Characteristics ( $V_{SS} = 0 V$ )

Characteristics		Sym-	Test Condition		-40°C		25°C			85°C		l lmit
		bol		V <sub>DD</sub> (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit
				5	4.95	_	4.95	5.00	_	4.95	_	
High-level voltage	High-level output	V <sub>OH</sub>	I <sub>OUT</sub>   < 1 μA	10	9.95	_	9.95	10.00	_	9.95	_	V
			$V_{IN} = V_{SS}, V_{DD}$	15	14.95		14.95	15.00		14.95		
			  I <sub>OUT</sub>   < 1 μA	5	_	0.05	_	0.00	0.05	_	0.05	
Low-level voltage	output	V <sub>OL</sub>	$V_{IN} = V_{SS}, V_{DD}$	10	_	0.05	_	0.00	0.05	_	0.05	V
			VIN - VSS, VDD	15	—	0.05	—	0.00	0.05	_	0.05	
			V <sub>OH</sub> = 4.6 V	5	-0.61	_	-0.51	-1.0	_	-0.42	_	
			V <sub>OH</sub> = 2.5 V	5	-2.50	_	-2.10	-4.0	_	-1.70	_	
Output hig	h current	I <sub>OH</sub>	V <sub>OH</sub> = 9.5 V	10	-1.50	_	-1.30	-2.2	_	-1.10	_	mA
			V <sub>OH</sub> = 13.5 V	15	-4.00	_	-3.40	-9.0	_	-2.80	_	
			$V_{IN} = V_{SS}, V_{DD}$									
		l <sub>OL</sub>	V <sub>OL</sub> = 0.4 V	5	0.61	_	0.51	1.2	_	0.42	_	mA
Output lov	v current		V <sub>OL</sub> = 0.5 V	10	1.50	_	1.3	3.2	_	1.10	_	
Output lov	v current		V <sub>OL</sub> = 1.5 V	15	4.00	_	3.4	12.0	_	2.80	_	
			$V_{IN} = V_{SS}, V_{DD}$									
		VIH	V <sub>OUT</sub> = 0.5 V, 4.5 V	5	3.5	_	3.5	2.75	_	3.5	_	V
Input high	voltage		V <sub>OUT</sub> = 1.0 V, 9.0 V	10	7.0	_	7.0	5.50	_	7.0	_	
inputnign	voitage		V <sub>OUT</sub> = 1.5 V, 13.5 V	15	11.0	_	11.0	8.25	_	11.0	_	
			$ I_{OUT}  < 1 \mu A$									
		VIL	V <sub>OUT</sub> = 0.5 V, 4.5 V	5	_	1.5	_	2.25	1.5	_	1.5	V
Input low	voltago		V <sub>OUT</sub> = 1.0 V, 9.0 V	10	_	3.0	_	4.50	3.0	_	3.0	
input low	voitage		V <sub>OUT</sub> = 1.5 V, 13.5 V	15	_	4.0	_	6.75	4.0	_	4.0	
			$ I_{OUT}  < 1 \mu A$									
Input	"H" level	l <sub>IH</sub>	V <sub>IH</sub> = 18 V	18	_	0.1		10 <sup>-5</sup>	0.1	_	1.0	μА
current	"L" level	I <sub>Ι</sub> L	V <sub>IL</sub> = 0 V	18	_	-0.1	_	-10 <sup>-5</sup>	-0.1	_	-1.0	μΑ
3-state output	"H" level	I <sub>DH</sub>	V <sub>OH</sub> = 18 V	18	_	0.4	_	10 <sup>-4</sup>	0.4	_	12	μА
leakage current	"L" level	I <sub>DL</sub>	V <sub>OL</sub> = 0 V	18	_	-0.4	_	-10 <sup>-4</sup>	-0.4	_	-12	, m
Outres 1		ply I <sub>DD</sub>	$V_{IN} = V_{SS}, V_{DD}$ (Note)	5	_	1	_	0.002	1	_	30	
Quiescent current	supply			10	_	2	_	0.004	2	-	60	μА
			(14016)	15	_	4		0.008	4	_	120	

Note: All valid input combinations.

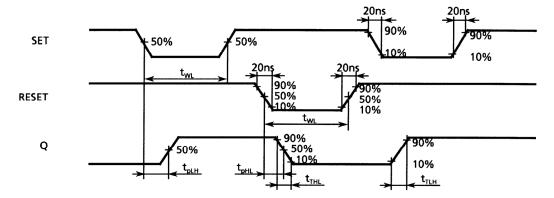


# Dynamic Electrical Characteristics (Ta = 25°C, $V_{SS}$ = 0 V, $C_L$ = 50 pF)

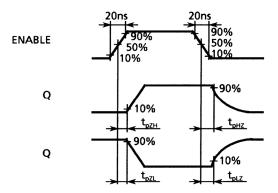
Characteristics	Symbol	Test Condition	Min	Typ	Max	Unit	
Characteristics	Symbol		V <sub>DD</sub> (V)	IVIIII	Тур.	IVIAX	Offic
Output transition time			5	_	70	200	
(low to high)	tTLH	_	10	_	35	100	ns
(low to flight)			15	_	30	80	
Output transition time			5	_	70	200	
(high to low)	t <sub>THL</sub>	_	10	_	35	100	ns
(High to low)			15	_	30	80	
Propagation delay time	<b>+</b>		5	_	90	300	
(SET, RESET-Q)	t <sub>pLH</sub> t <sub>pHL</sub>	_	10	_	45	140	ns
(SET, NESET-W)			15	_	35	100	
3-state propagation delay time	+		5	_	55	180	
(ENABLE-Q)	t <sub>pHZ</sub>	$R_L = 1 k\Omega$	10	_	35	100	ns
(LNADLL-Q)	t <sub>pLZ</sub>		15	_	30	70	
3-state propagation delay time	t		5	_	55	180	
(ENABLE-Q)	t <sub>pZH</sub>	$R_L = 1 \text{ k}\Omega$	10	_	30	100	ns
(LIVABLE-Q)	t <sub>pZL</sub>		15	_	25	70	
Min pulso width			5	_	25	160	
Min pulse width (SET, RESET)	tw∟	_	10	_	20	80	ns
(SEI, RESEI)			15		20	40	
Input capacitance	C <sub>IN</sub>	_		_	5	7.5	pF

### **Waveforms for Measurement of Dynamic Characteristics**

### Waveform 1



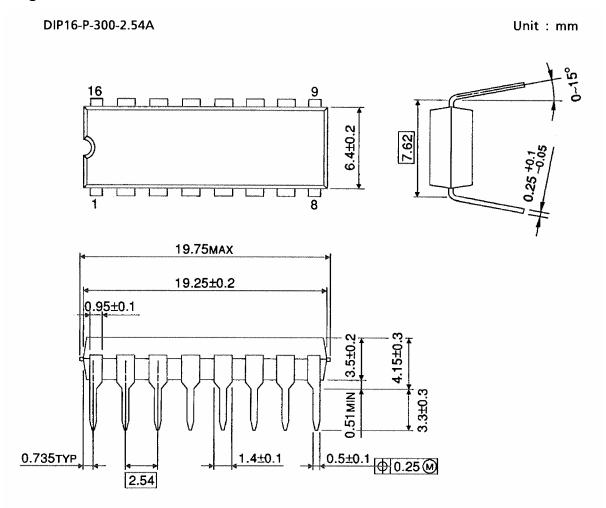
### Waveform 2



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### **Package Dimensions**

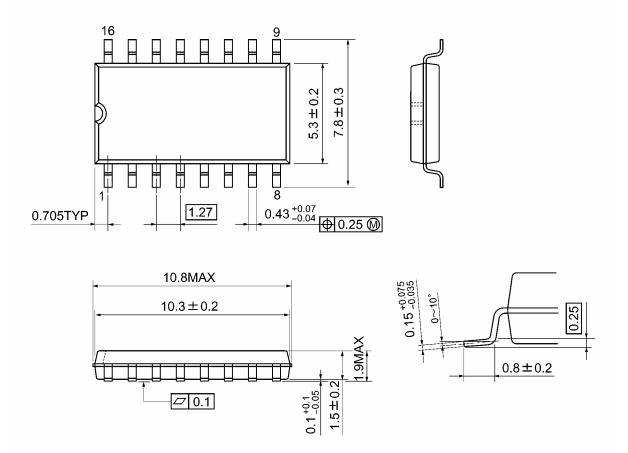


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Weight: 1.00 g (typ.)

### **Package Dimensions**

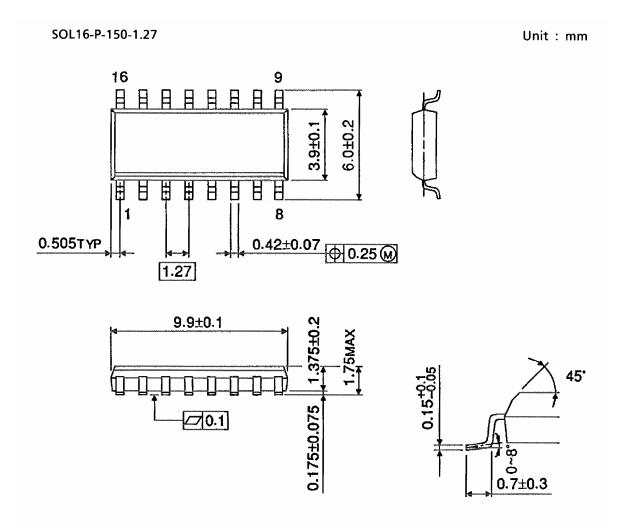
SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)



### **Package Dimensions (Note)**



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Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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